

<b>Notice of References Cited</b>	Application/Control No. 10/588,287	Applicant(s)/Patent Under Reexamination FUJINO ET AL.	
	Examiner Deborah Yee	Art Unit 1793	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,338,763	01-2002	Hashimura et al.	148/333
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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